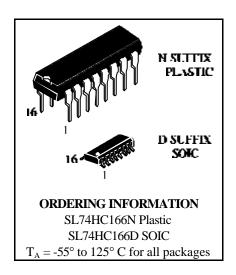
8-Bit Serial or Parallel-Input/ Serial-Output Shift Register

High-Performance Silicon-Gate CMOS

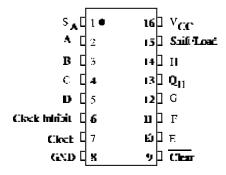
The SL74HC166 is identical in pinout to the LS/ALS166. The device inputs are compatible with standard CMOS outputs; with pullup resistors, they are compatible with LS/ALSTTL outputs.

This device is a parallel-in or serial-in, serial-out shift register with gated clock inputs and an overriding clear input. The shift/load input establishes the parallel-in or serial-in mode. When high, this input enables the serial data input and couples the eight flip-flops for serial shifting with each clock pulse. Synchronous loading occurs on the next clock pulse when this is low and the parallel data inputs are enabled. Serial data flow is inhibited during parallel loading. Clocking is done on the low-to-high level edge of the clock pulse via a two input positive NOR gate, which permits one input to be used as a clock enable or clock inhibit function. Clocking is inhibited when either of the clock inputs are held high, holding either input low enables the other clock input. This will allow the system clock to be free running and the register stopped on command with the other clock input. A change from low-to-high on the clock inhibit input should only be done when the clock input is high. A buffered direct clear input overrides all other inputs, including the clock, andsets all flip-flop to

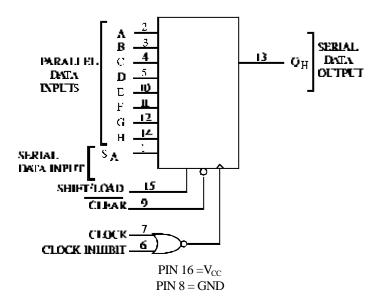
- Outputs Directly Interface to CMOS, NMOS, and TTL
- Operating Voltage Range: 2.0 to 6.0 V
- Low Input Current: 1.0 μA
- High Noise Immunity Characteristic of CMOS Devices



PIN ASSIGNMENT



LOGIC DIAGRAM



MAXIMUM RATINGS*

| Symbol | Parameter | Value | Unit |
|------------------|---|-----------------------|------|
| V_{CC} | DC Supply Voltage (Referenced to GND) | -0.5 to +7.0 | V |
| $V_{\rm IN}$ | DC Input Voltage (Referenced to GND) | -1.5 to V_{CC} +1.5 | V |
| V_{OUT} | DC Output Voltage (Referenced to GND) | -0.5 to V_{CC} +0.5 | V |
| I_{IN} | DC Input Current, per Pin | ±20 | mA |
| I_{OUT} | DC Output Current, per Pin | ±25 | mA |
| I_{CC} | DC Supply Current, V _{CC} and GND Pins | ±50 | mA |
| P_{D} | Power Dissipation in Still Air, Plastic DIP+ SOIC Package+ | 750 500 | mW |
| Tstg | Storage Temperature | -65 to +150 | °C |
| $T_{\rm L}$ | Lead Temperature, 1 mm from Case for 10 Seconds (Plastic DIP or SOIC Package) | 260 | °C |

^{*}Maximum Ratings are those values beyond which damage to the device may occur.

Functional operation should be restricted to the Recommended Operating Conditions.

SOIC Package: : - 7 mW/°C from 65° to 125° C

RECOMMENDED OPERATING CONDITIONS

| Symbol | Parameter | Min | Max | Unit |
|---------------------------------|---|-------------|--------------------|------|
| V_{CC} | DC Supply Voltage (Referenced to GND) | 2.0 | 6.0 | V |
| $V_{\rm IN}, V_{ m OUT}$ | DC Input Voltage, Output Voltage (Referenced to GND) | 0 | V_{CC} | V |
| T_{A} | Operating Temperature, All Package Types | -55 | +125 | °C |
| t _r , t _f | Input Rise and Fall Time (Figure 1) $V_{CC} = 2.0 \text{ V} $ $V_{CC} = 4.5 \text{ V} $ $V_{CC} = 6.0 \text{ V} $ | 0 0 0 | 1000 500 400 | ns |

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V_{IN} and V_{OUT} should be constrained to the range $GND \leq (V_{IN} \text{ or } V_{OUT}) \leq V_{CC}$.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.

⁺Derating - Plastic DIP: - 10 mW/°C from 65° to 125°C

DC ELECTRICAL CHARACTERISTICS (Voltages Referenced to GND)

| | | | V _{CC} | Guar | anteed L | imit | |
|-------------------|--|--|-------------------|----------------------|--------------------|--------------------|------|
| Symbol | Parameter | Test Conditions | V | 25 °C to -55°C | ≤85 °C | ≤125 °C | Unit |
| V _{IH} | Minimum High-Level Input Voltage | V_{OUT} =0.1 V or V_{CC} -0.1 V I_{OUT} $\leq 20 \mu A$ | 2.0 4.5 6.0 | 1.5 3.15 4.2 | 1.5 3.15 4.2 | 1.5 3.15 4.2 | V |
| $V_{\rm IL}$ | Maximum Low -Level Input Voltage | V_{OUT} =0.1 V or V_{CC} -0.1 V $I_{OUT}I \le 20 \mu\text{A}$ | 2.0 4.5 6.0 | 0.3 0.9 1.2 | 0.3 0.9 1.2 | 0.3 0.9 1.2 | V |
| V_{OH} | Minimum High-Level Output Voltage | $ V_{\rm IN} = V_{\rm IH} \text{ or } V_{\rm IL} $ $ I_{\rm OUT} \le 20 \mu\text{A} $ | 2.0 4.5 6.0 | 1.9 4.4 5.9 | 1.9 4.4 5.9 | 1.9 4.4 5.9 | V |
| | | $\begin{aligned} & V_{\rm IN} {=} V_{\rm IH} \text{ or } V_{\rm IL} \\ & \mid I_{\rm OUT} \mid \leq 4.0 \text{ mA} \\ & \mid I_{\rm OUT} \mid \leq 5.2 \text{ mA} \end{aligned}$ | 4.5 6.0 | 3.98 5.48 | 3.84 5.34 | 3.7 5.2 | |
| V_{OL} | Maximum Low-Level Output Voltage | $ \begin{aligned} &V_{\rm IN} = &V_{\rm IH} \text{ or } V_{\rm IL} \\ & I_{\rm OUT} \leq 20 \ \mu A \end{aligned} $ | 2.0 4.5 6.0 | 0.1 0.1 0.1 | 0.1 0.1 0.1 | 0.1 0.1 0.1 | V |
| | | $ \begin{aligned} & V_{\rm IN} {=} V_{\rm IH} \text{ or } V_{\rm IL} \\ & \mid I_{\rm OUT} \mid \leq 4.0 \text{ mA} \\ & \mid I_{\rm OUT} \mid \leq 5.2 \text{ mA} \end{aligned} $ | 4.5 6.0 | 0.26 0.26 | 0.33 0.33 | 0.4 0.4 | |
| $I_{\rm IN}$ | Maximum Input Leakage Current | V _{IN} =V _{CC} or GND | 6.0 | ±0.1 | ±1.0 | ±1.0 | μА |
| I_{CC} | Maximum Quiescent Supply Current (per Package) | $V_{\rm IN} = V_{\rm CC}$ or GND $I_{\rm OUT} = 0 \mu A$ | 6.0 | 8.0 | 80 | 160 | μΑ |

FUNCTION TABLE

| Inputs | | | | | | Internal Outputs | | Output |
|--------|------------|------------------|-------|-------|----------------|---------------------|-------------|----------|
| Clear | Shift/Load | Clock Inhibit | Clock | S_A | Parallel AH | Q_A | $Q_{\rm B}$ | Q_{H} |
| L | X | X | X | X | X | L | L | L |
| Н | X | X | / | X | X | No change | | |
| Н | L | L | | X | ah | a | b | h |
| Н | Н | L | | Н | X | Н | Q_{An} | Q_{Gn} |
| Н | Н | L | | L | X | L | Q_{An} | Q_{Gn} |
| Н | X | Н | X | X | X | No change | | |

X = don' t care

a...h = the level of steady state input voltage at input A trough H respectively

$\textbf{AC ELECTRICAL CHARACTERISTICS}(C_L = 50 pF, Input \ t_r = t_f = 6.0 \ ns)$

| | | V_{CC} | Gu | Guaranteed Limit | | |
|----------------------------|---|-------------------|-------------------|------------------|-----------------|------|
| Symbol | Parameter | V | 25 °C to -55°C | ≤85°C | ≤125°C | Unit |
| f_{max} | Minimum Clock Frequency (50% Duty Cycle) (Figures 2 and 4) | 2.0 4.5 6.0 | 6.0 31 36 | 5.0 25 28 | 4.2 21 25 | MHz |
| $t_{\rm PLH}, t_{\rm PHL}$ | Maximum Propagation Delay, Clock (or Clock Inhibit) to Q _H (Figures 2,3 and 4) | 2.0 4.5 6.0 | 140 28 24 | 175 35 30 | 210 42 36 | ns |
| t _{PHL} | Maximum Propagation Delay , Clear to $Q_{\rm H}$ (Figures 1 and 4) | 2.0 4.5 6.0 | 150 30 26 | 200 40 34 | 230 48 40 | ns |
| t_{TLH}, t_{THL} | Maximum Output Transition Time, Any Output (Figures 1 and 4) | 2.0 4.5 6.0 | 75 16 14 | 95 20 18 | 110 25 20 | ns |
| C_{IN} | Maximum Input Capacitance | - | 10 | 10 | 10 | pF |

| Power Dissipation Capacitance (Per Package) Typical @25°C,V _{CC} =5.0 V | |
|--|----|
| C_{PD} Used to determine the no-load dynamic power consumption: $P_{D}=C_{PD}V_{CC}^{2}f+I_{CC}V_{CC}$ | pF |

$\textbf{TIMING REQUIREMENTS}(C_L = 50 pF, Input \ t_r = t_f = 6.0 \ ns)$

| | | V_{CC} | Guara | Guaranteed Limit | | |
|----------------|--|-------------------|-------------------|------------------|-----------------|------|
| Symbol | Parameter | V | 25 °C to -55°C | ≤85°C | ≤125°C | Unit |
| $t_{ m su}$ | Minimum Setup Time, Shift/Load to Clock (Figure 3) | 2.0 4.5 6.0 | 80 16 14 | 100 20 18 | 120 24 20 | ns |
| $t_{ m su}$ | Minimum Setup Time, Data before Clock (or Clock Inhibit) (Figure 3) | 2.0 4.5 6.0 | 80 16 14 | 100 20 18 | 120 24 20 | ns |
| t _w | Minimum Pulse Width, Clock (or Clock Inhibit) (Figure 2) | 2.0 4.5 6.0 | 80 16 14 | 100 20 17 | 120 24 20 | ns |

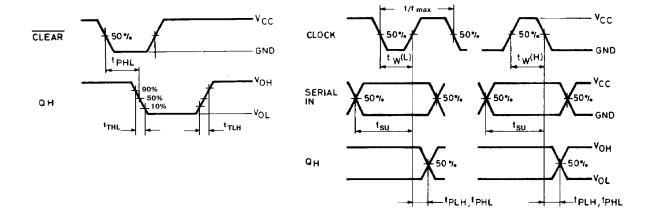


Figure 1. Switching Waveforms

Figure 2. Switching Waveforms

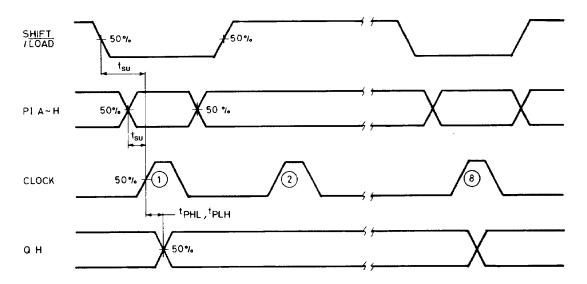
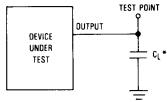


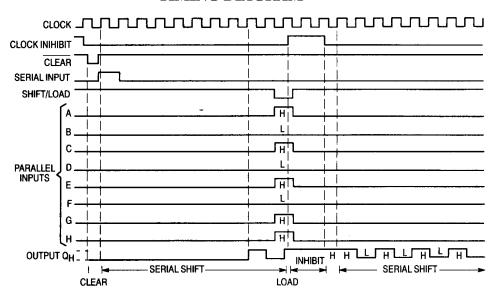
Figure 3. Switching Waveforms



^{*}Includes all probe and jig capacitance.

Figure 4. Test Circuit

TIMING DIAGRAM



EXPANDED LOGIC DIAGRAM

